



(12) Patent Application Publication
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(43) **Pub. Date:** **Jun. 27, 2024**

(52) **U.S. Cl.**
CPC **H04B 17/102** (2015.01); **G01R 29/10**
(2013.01); **H04B 17/11** (2015.01)

(57) **ABSTRACT**

A method determines corrected TRP or TIS of an AUT in a near-field test chamber, the AUT having a phase center offset from a rotation center of the test chamber. The method includes performing EIRP or EIS measurements of the AUT at first sampling grid points on a first closed-surface geometric shape centered at the rotation center; mapping second sampling grid points to the first closed-surface geometric shape to provide mapped sampling grid points on the first closed-surface geometric shape, where the second sampling grid points are on a second closed-surface geometric shape centered at the phase center of the AUT; determining estimated EIRPs or EISs at the mapped sampling grid points using the EIRP or EIS measurements; scaling the estimated EIRPs or EISs at the mapped sampling grid points to provide scaled EIRPs or EISs; and calculating the corrected TRP or TIS based on the scaled EIRPs or EISs.

(86) PCT No.: **PCT/CN2020/122908**

§ 371 (c)(1),

(2) Date: **Apr. 13, 2023**

Publication Classification

(51) **Int. Cl.**
H04B 17/10 (2006.01)
G01R 29/10 (2006.01)
H04B 17/11 (2006.01)

